

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

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Page 1 of 1

**U.S. PATENT DOCUMENTS**

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*	B US-2004/0056260	03-2004	Slater et al.	257/079
*	C US-2002/0123164	09-2002	Slater et al.	438/39
*	D US-2004/0032013	02-2004	Cobbley et al.	257/678
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K	US-			
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M	US-			

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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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